

Program at a glance

Monday May23rd

| | | |
|---------------|---|---|
| 14:00 - 18:00 | AUDITORIUM R1 (TSS@ETS) Track A Embedded Memory Testing: Fault Models, Test Algorithms, MBIST and Industrial Results | AUDITORIUM R9 (TSS@ETS) Track B Design for Test and Fault Tolerance for Nanoscale Circuits |
|---------------|---|---|

Tuesday May24th

| | R1 ABEL | R2 IBSEN | R3 NANSEN | R54 GRIEG | LOBBY AREA/CANTEEN |
|-------|-----------------------|---|-------------------------------------|------------------|--------------------|
| 09:00 | Opening session | | | | |
| 11:00 | | | | | Posters and coffee |
| 12:00 | Converter testing | Security | Industrial Testing (Vendor session) | Power switches | |
| 13:00 | | | | | Lunch in canteen |
| 14:30 | Emerging technologies | 3D technology | Mixed signal and RF test | | |
| 16:00 | | | | | Posters and coffee |
| 17:00 | Dependability | Test data compression, compaction and diagnosis | Test Equipment 1 (Vendor session) | | |
| 18:30 | | | PhD forum | | |

Wednesday May25th

| | R1 ABEL | R2 IBSEN | R3 NANSEN | LOBBY AREA/CANTEEN |
|-------|---|--------------------------------|---|------------------------------|
| 09:00 | Advances in Test | Contactless and memory testing | Test-EDA (Vendor session) | |
| 10:30 | | | | Posters and coffee |
| 11:30 | ATPG 1 | Analog production test | Test Equipment 2 (Vendor session) | |
| 13:00 | | | | Lunch in canteen |
| 14:30 | Embedded tutorial A: Formal Verification of SoC - Industrial Experiences and Scientific Perspective | | Embedded tutorial B: Towards Variation-Aware Test | |
| 15:45 | | | | Social event - bus departure |

Thursday May26th

| | R1 ABEL | R2 IBSEN | R3 NANSEN | LOBBY AREA/CANTEEN |
|-------|--|--|---|---|
| 09:00 | ATPG 2 | Post silicon debug | Industrial testing (Vendor session) | |
| 10:30 | | | | Poster Session 4 and coffee. TTTC's E.J. McCluskey Best Doctoral Thesis Award and Student Work-in-Progress |
| 11:30 | Panel A Working Silicon versus Working Board/System: Closing the Gap | Panel B Taking the Sense and Nonsense Out of Temperature-Aware Testing | Panel C BIST for non-digital IPs: can we (do we need to) estimate test costs before production? | |
| 13:00 | | | | Lunch in canteen |
| 14:30 | Session 7 - Diagnosis | | | |
| 16:00 | Closing | | | |

Fringe workshops: DDT, IWPVTD, LPonTR. See links to each workshop on the ETS'11 Web site. Starts Thursday May 26 at 16:45. Continues Friday May 27 at 08:30 and finishes at 16:00.